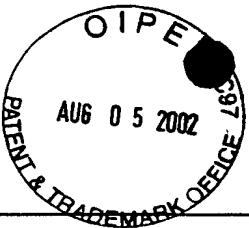




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List of Patent and Publications Cited by Applicant (Use several sheets if necessary)			Applicant Dawn A. Bonnell, et al.	
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<i>WB</i>	AD	<i>Buchanan, R., Ceramic Materials for Electronics, 1991, Marcel Dekker, Inc., New York</i>		
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<i>WB</i>	AZ	Kim, S.H. et al., "Effect of MnO addition on the electrical properties of Nb-doped SrTiO ₃ varistor", <i>Materials in Science & Engineering.</i> , 1999, 56, 12-20		
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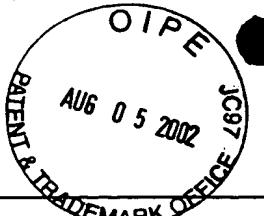
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